

New Generation Grace Inertia Connector 3.3

1. INTRODUCTION

1.1 Purpose

The purpose of this test is to evaluate the performance of New Generation Grace Inertia Connector 3.3 where the raw material of Rec terminal (1983780-1) is changed from 3-704937-3 to 2-705758-5 for VAVE (TEBIT 245347). Testing was performed on below products to determine its compliance with the requirements of 108-106094 Rev. D.

1.2 Scope

This specification covers the electrical, mechanical, and environmental performance for New Generation Grace Inertia Connector 3.3. Testing was performed at TE Connectivity Shanghai Electrical Test Laboratory (Building ID 554) between 2021-03-25 and 2021-04-12.

The associated test number is TP-21-00620.

1.3 Conclusion

Based on the test results, all samples meet the requirement according to customer requirement. The results in this report only effect on the sampling specimens.

1.4 Test Specimens

Specimens with the following part numbers were used for test:

Test Group	Part No.	Description	Qty. (pcs)
	1983780-1	New GIC 3.3 Rec contact with 24AWG UL1015	5
1	1983780-1	New GIC 3.3 Rec contact with 20AWG UL1007	5
	1983780-1	New GIC 3.3 Rec contact with 22AWG UL1007	5
2	1983780-1	New GIC 3.3 Rec contact with 20AWG UL1007	15
2	1-1971906-7	NEW GIC 3.3 HEADER ASSY 14POS	3
	1983780-1	New GIC 3.3 Rec contact with 20AWG UL1007	70
3	1-1971905-7	NEW GIC 3.3 PLUG HOUSING 14POS	5
	1-1971906-7	NEW GIC 3.3 HEADER ASSY 14POS	5
	1-1971905-6	NEW GIC 3.3 PLUG HOUSING 12POS	9
	1983780-1	New GIC 3.3 Rec contact with 20AWG UL1007	36
4	1983780-1	New GIC 3.3 Rec contact with 22AWG UL1007	36
	1983780-1	New GIC 3.3 Rec contact with 24AWG UL1015	36
	1-1971906-6	NEW GIC 3.3 HEADER ASSY 12POS	9
	1983780-1	New GIC 3.3 Rec contact with 20AWG UL1007	42
5	1-1971906-7	NEW GIC 3.3 HEADER ASSY 14POS	3
	1-1971905-7	NEW GIC 3.3 PLUG HOUSING 14POS	3
	1-1971906-7	NEW GIC 3.3 HEADER ASSY 14POS	3
6	1-1971905-7	NEW GIC 3.3 PLUG HOUSING 14POS	3
	1983780-1	New GIC 3.3 Rec contact with 20AWG UL1007	42



1.5 Test Sequence

	Test Group								
Test Item	1	2	3	4	5	6			
	Test Sequence								
Contact Insertion Force			2						
Crimp Tensile Strength Test	2								
Dielectric Withstanding Voltage					8				
Dry Heat						3			
Durability Test		4	6						
Examination of Product	1,3	1,7	1,10	1,3	1,5	1,4			
Humidity and Temperature Cycling					4				
Insulation Resistance					3,7				
Low Level Contact Resistance			4,7		2,6	2,5			
Mating Force		2,5	3						
Retention Force Test			9						
Temperature Rise				2					
Unmating Force		3,6	5,8						

Note: a). Test group defined per customer requirement.

b). Numbers indicate sequence in which tests are performed.

1.6 Environmental Conditions

Unless otherwise stated, the following environmental conditions prevailed during testing:

Temperature: 15 °C to 35 °C Relative Humidity: 25 % to 75 %

2. TEST PROCEDUES

2.1 Contact Insertion Force

Measure the force required to insert contact into housing.

Requirements: 8.82 N Max. per contact

Test Method: EIA-364-05C-2020

2.2 Crimp Tensile Strength Test

Apply an axial pull-off load to crimped wire of contact secured on the tester. Operation speed: 100 mm/min. Subject take

insulation barrel away.

Requirement: 58.8 N min. for 20 AWG, 49 N min. for 22 AWG, 29.4 N min. for 24 AWG

Test Method: EIA-364-08C-2015

2.3 Dielectric Withstanding Voltage

Apply a test potential of 1.5 kV AC for 1 minute. Test between adjacent circuits and between the surface of housing and contact of mated connectors. Current leakage: 5 mA Max.

Requirements: No breakdown of flashover shall occur.

Test Method: EIA-364-20F-2019

2.4 Dry Heat

Mated specimens were exposed to a temperature of 105 °C for 96 hours.

Requirement: No evidence of physical damage was visible.

Test Method: EIA-364-17C-2011

2.5 Durability Test

Specimens were mated and unmated 30 times at a maximum rate of 600 cycles per hour.

Requirement: No evidence of physical damage was visible.

Test Method: EIA-364-09D-2018

2.6 Examination of Product

Visual inspection of product.

Requirement: No evidence of physical damage was visible.

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Test Method: EIA-364-18B-2017

2.7 Humidity and Temperature Cycling

Mated specimens were exposed to 10 cycles (10 days) of humidity-temperature cycling. Each cycle consisted of temperature between 25 °C and 65 °C and humidity between 80 %RH~90 %RH.

Requirement: No evidence of physical damage was visible. Test Method: MIL-STD-202G, Method 106 Condition D

2.8 Insulation Resistance

Impressed a test voltage of 500 V DC. Test between adjacent circuits and between the surface of housing and contact of mate connectors.

Requirement: 1000 M Ω minimum for initial measurement, 500 M Ω minimum for final measurement.

Test Method: EIA-364-21E-2014

2.9 Low Level Contact Resistance

Measure and record the contact resistance with a test current of 100 milliamperes maximum and 20 millivolts open circuit (source) voltage maximum.

Requirement: 10 milliohms maximum for initial measurement. 20 milliohms maximum for final measurement.

Test Method: EIA-364-23C-2006

2.10 Connector Mating force

Measure the force required to mate connectors without Housing Lock. Operation speed:100mm/min.

Requirement: Mating force: (5.88×14 Pos.) N = 82.32 N Max.

Test Method: EIA-364-13E-2011

2.11 Contact Mating force

Measure the force required to mate contacts. Operation speed:100mm/min.

Requirement: Mating force: 5.88 N Max. (1st~30th)

Test Method: EIA-364-13E-2011

2.12 Retention Force Test

Apply an axial pull-off load to crimped wire. Operation speed: 100mm/min.

Requirements:19.8 N (2kgf) Min. without TPA for all Wire Size

Test Method: TE 109-39 A

2.13 Temperature Rise

Measure temperature rising by energized current. Subject measurement must do at the place of no influence from convection of air. And contacts shall be assembled in housing all of circuits. The thermocouple shall be attached to the contact of center circuit number. Under loaded specified current as followed: 3.5 A for 20 AWG; 2.5 A for 22 AWG; 2.2 A for 24 AWG.

Requirement: 30 °C Max. Test Method: EIA-364-70C-2014

2.14 Connector Unmating Force

Measure the force required to un-mate connectors without housing lock. Operation speed:100mm/min.

Requirement: (0.58×14 Pos.) N= 8.12 N Min. (1st), (0.29×14 Pos.) N= 4.06 N Min. (30th)

Test Method: EIA-364-13E-2011

2.15 Contact Unmating Force

Measure the force required to un-mate contacts. Operation speed:100mm/min.

Requirement: 0.34 N (1st), 0.25 N (30th)

Test Method: EIA-364-13E-2011

3. SUMMARY OF TEST

Croun	SN	Description	Test Item	Ot: (noo)		Test	Result		Doguiromont	Conducion	View
Group	SIN	Description	restitem	Qty(pcs)	Max	Min	Avg	Unit	Requirement	Conclusion	view
	1	/	Examination of Product	5	No phy	/sical da	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
1	2	20 AWG	Crimp Tensile Strength Test	5	88.3	75.5	83.1	N	58.8 N Min.	Meet Spec.	<u>View</u>

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Group	SN	Description	Test Item	Qty(pcs)	Max	Min	Avg	Unit	Requirement	Conclusion	View
	2	22 AWG	Crimp Tensile Strength Test	5	78.4	56.1	71.0	N	49 N Min.	Meet Spec.	<u>View</u>
	2	24 AWG	Crimp Tensile Strength Test	5	49.4	40.5	44.2	N	29.4 N Min.	Meet Spec.	View
	3	/	Examination of Product	5	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	1	/	Examination of Product	3	No physical damage.		/	No physical damage.	Meet Spec.	<u>View</u>	
	2	1 ^{st-} Mating	Mating Force	3	2.2	1.5	1.9	N	5.88 N Max.	Meet Spec.	<u>View</u>
	3	1 st - Unmating	Unmating Force	3	1.6	0.8	1.1	N	0.34 N Min.	Meet Spec.	<u>View</u>
2	4	/	Durability Test	3	No phy	/sical da	amage.	/	No physical damage.	Meet Spec.	View
	5	30 th -Mating	Mating Force	3	2.5	1.3	1.9	N	5.88 N Max.	Meet Spec.	<u>View</u>
	6	30 th - Unmating	Unmating Force	3	1.8	0.8	1.2	N	0.25 N Min.	Meet Spec.	<u>View</u>
	7	/	Examination of Product	3	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	1	/	Examination of Product	5	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	2	/	Contact Insertion Force	5	8.6	4.1	6.3	N	8.82 N Max.	Meet Spec.	<u>View</u>
	3	/	Mating force	5	34.4	33.5	33.9	N	82.32 N Max.	Meet Spec.	<u>View</u>
	4	/	Low Level Contact Resistance	5	5.43	3.51	4.40	mΩ	10 mΩ Max.	Meet Spec.	View
3	5	1 st - Unmating	Unmating Force	5	23.8	20.9	22.7	N	8.12 N Min.	Meet Spec.	View
	6	/	Durability Test	5	No phy	No physical damage.		/	No physical damage.	Meet Spec.	<u>View</u>
	7	/	Low Level Contact Resistance	5	6.66	4.10	4.73	mΩ	20 mΩ Max.	Meet Spec.	<u>View</u>
	8	30 th - Unmating	Unmating Force	5	30.5	20.5	24.2	N	4.06 N Min.	Meet Spec.	<u>View</u>
	9	/	Retention Force Test	5	40.9	20.2	30.1	N	19.8 N Min.	Meet Spec.	<u>View</u>
	10	/	Examination of Product	5	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	1	/	Examination of Product	9	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	2	24 AWG	Temperature Rise	3	14.1	12.3	13.4	°C	30 °C Max.	Meet Spec.	<u>View</u>
4	2	22 AWG	Temperature Rise	3	15.2	12.3	14.0	$^{\circ}$ C	30 °C Max.	Meet Spec.	<u>View</u>
	2	20 AWG	Temperature Rise	3	24.4	15.5	20.1	$^{\circ}$ C	30 °C Max.	Meet Spec.	<u>View</u>
	3	/	Examination of Product	9	No phy	sical da	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
5	1	/	Examination of Product	3	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
5	2	/	Low Level Contact	3	5.60	3.97	4.44	mΩ	10 mΩ Max.	Meet Spec.	<u>View</u>

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Group	SN	Description	Test Item	Oty/pag)		Test	Result		Requirement	Conclusion	View
Gloup	SIN	Description	restitem	Qty(pcs)	Max	Min	Avg	Unit	Requirement	Conclusion	view
			Resistance								
	3	/	Insulation Resistance	3	7.48	1.15	2.56	10 ¹² Ω	1000 MΩ Min.	Meet Spec.	<u>View</u>
	4	/	Humidity and Temperature Cycling	3	No phy	/sical da	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	5	/	Examination of Product	3	No phy	/sical da	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	6	/	Low Level Contact Resistance	3	6.16	3.97	4.47	mΩ	20 mΩ Max.	Meet Spec.	<u>View</u>
	7	/	Insulation Resistance	3	72.77	6.84	16.70	10 ⁸ Ω	500 MΩ Min.	Meet Spec.	<u>View</u>
	8	/	Dielectric Withstanding Voltage	3		reakdo [,] ashove		/	No breakdown or flashover.	Meet Spec.	<u>View</u>
	1	/	Examination of Product	3	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	2	/	Low Level Contact Resistance	3	4.86	3.97	4.48	mΩ	10 mΩ Max.	Meet Spec.	<u>View</u>
6	3	/	Dry Heat	3	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	4	/	Examination of Product	3	No phy	sical d	amage.	/	No physical damage.	Meet Spec.	<u>View</u>
	5	/	Low Level Contact Resistance	3	5.02	3.62	4.26	mΩ	20 mΩ Max.	Meet Spec.	<u>View</u>

4. VALIDATION

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